

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	602	((356/237.4,237.5,244).ccls.) and ((wafer or semiconductor) near10 (test or tests or testing or inspect\$ or station or convey\$ or monitor\$ or detect\$))	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:18
L2	194	(((356/237.4,237.5,244).ccls.) and ((wafer or semiconductor) near10 (test or tests or testing or inspect\$ or station or convey\$ or monitor\$ or detect\$))) and ((wafer or semiconductor) near15 rotat\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:19
L3	17092	(workstations or chambers) near8 open	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:20
L4	0	2 and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:20
L5	20359	(workstations or chambers) near12 open	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:20
L6	0	2 and 5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:21
L7	0	1 and 5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/12/05 13:21